

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DKT. NO.
500.34077CC3SERIAL NO.
09/900,144INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

(Use several sheets if necessary)

APPLICANT
MAKI, et al.FILING DATE
July 9, 2001GROUP
3737

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
<i>AA</i>	AA 4,281,645	8-4-81	J8bsis			
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation /Abstract	
						Yes	No
<i>AM</i>	AM 03-067409	3-22-91	Japan			X	
	AN 05-103773	4-27-93	Japan			X	
	AO 05-103837	4-27-93	Japan			X	
	AP 07-049304	2-21-95	Japan			X	
	AQ 07-049307	2-21-95	Japan			X	
	AR 07-113743	5-2-95	Japan			X	
	AS 07-120384	5-12-95	Japan			X	
	AT 07-128231	5-19-95	Japan			X	
<i>AU</i>	AU 93/25145	12-23-93	WO			X	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>AV</i>	AV	Feng, et al., "Monte Carlo Simulations of Photon Migration Path Distributions in Multiple Scattering Media", SPIE, vol. 1888, pp. 78-89, 1993
	AW	
	AX	
	AY	
	AZ	
Examiner <i>E. J. ...</i>		Date Considered 01/06/2006



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						Yes	No
AM	93/25141	12-23-93	WO			X	
AN	6-14908	1-25-94	Japan			X	
AO	64-46439	2-20-89	Japan			X	
AP	57-115232	7-17-82	Japan			X	
AQ							
AR							
AS							
AT							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

AU	
AV	
AW	
AX	
AY	
AZ	
Examiner <i>Ellen Hambrick</i>	Date Considered 1/6/2006